

### Short description

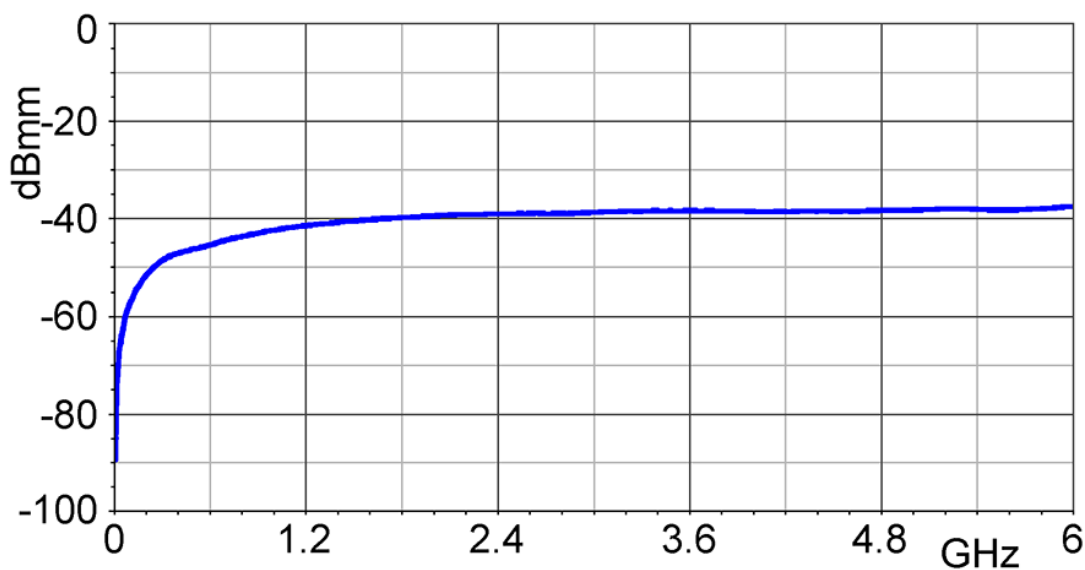
The electrode on the probe head of the XFS-E 09s scanner probe detects electrical fields which, for example are decoupled above the IC's surface. The probe's resolution allows for measurements with a distance of 0.5 mm to 10 mm above an assembly. For measurement, the E-field probe is placed on the target.

The XSF-E 09s is a passive near-field probe. To measure, the E-field probe is positioned above or onto components and printed circuit boards. It has a current attenuating sheath and, therefore, its upper half is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input. The E-field scanner probe has an internal terminating resistance.

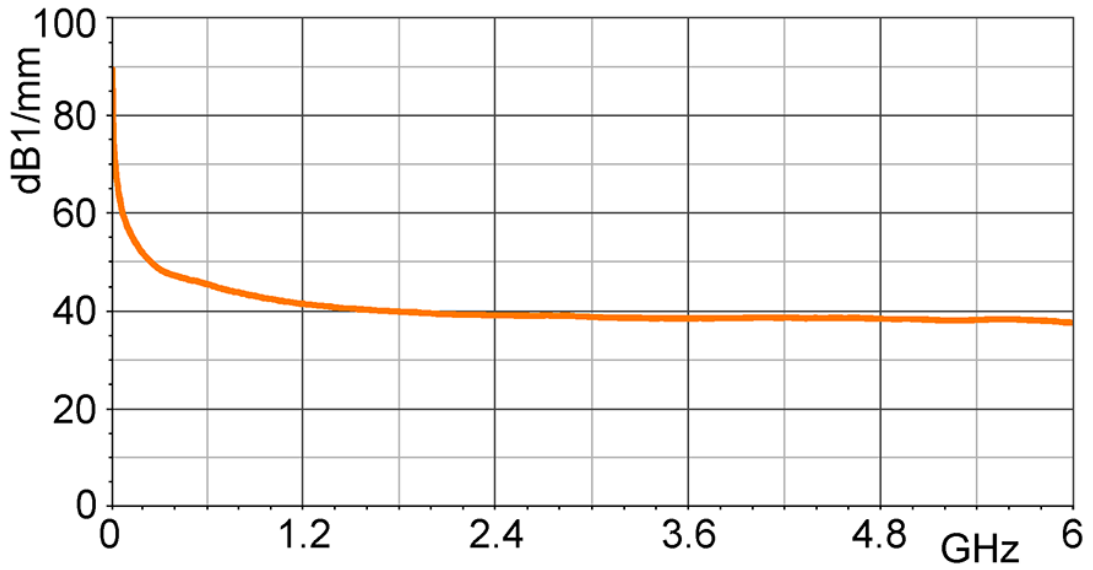
### Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	$\approx 0.2$ mm
Probe head dimensions	$\approx (10 \times 10)$ mm
Connector - output	SMA, male, jack

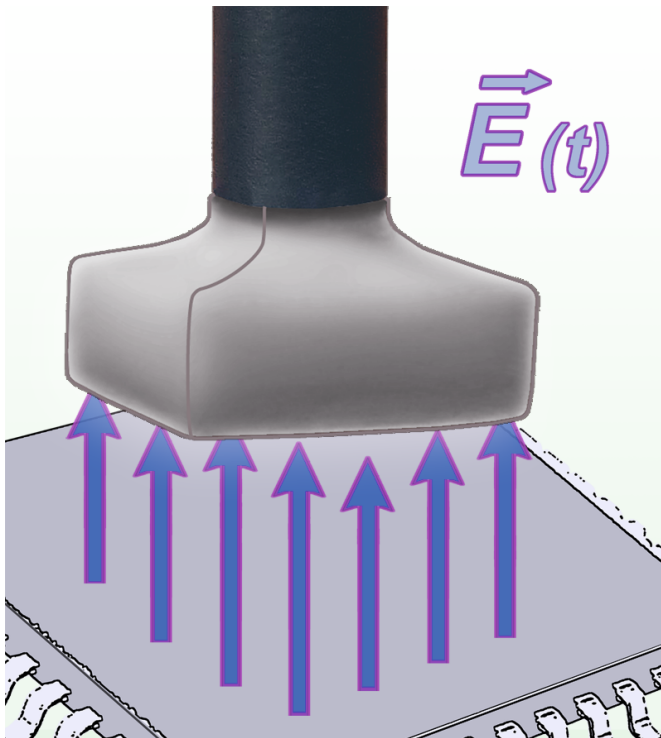
Frequency response [dB $\mu$ V] / [dB $\mu$ A/m]



E- field correction curve [dB $\mu$ V/mm] / [dB $\mu$ V]



Measuring principles



# XFS-E 09s

Scanner Probe 30 MHz up to 6 GHz

